

OptiMOS™ - 6 Power-Transistor

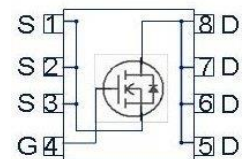
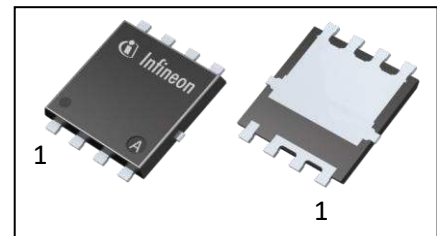
Features

- OptiMOS™ - power MOSFET for automotive applications
- N-channel - Enhancement mode - Normal Level
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green Product (RoHS compliant)
- 100% Avalanche tested

Product Summary

| | | |
|------------------|-----|----|
| V_{DS} | 40 | V |
| $R_{DS(on),max}$ | 0.6 | mΩ |
| I_D | 120 | A |

PG-TDSON-8-53



| Type | Package | Marking |
|------------------|---------------|----------|
| IAUC120N04S6N006 | PG-TDSON-8-53 | 6N04N006 |

Maximum ratings, at $T_j=25\text{ °C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Value | Unit |
|----------------------------------------------|-------------------|---------------------------------------------------------------------------|--------------|------|
| Drain current | I_D | $V_{GS}=10V$, Chip Limitation ^{1,2)} | 405 | A |
| | | $V_{GS}=10V$, DC current ³⁾ | 120 | |
| | | $T_a=85\text{ °C}$, $V_{GS}=10V$, R_{thJA} on 2s2p ^{4,5)} | 55 | |
| Pulsed drain current ⁵⁾ | $I_{D,pulse}$ | $T_C=25\text{ °C}$, $t_p=100\mu s$ | 1500 | |
| Avalanche energy, single pulse ²⁾ | E_{AS} | $I_D=60A$, $R_G=25\Omega$ | 750 | mJ |
| Avalanche current, single pulse | I_{AS} | $R_G=25\Omega$ | 120 | A |
| Gate source voltage | V_{GS} | - | ± 20 | V |
| Power dissipation | P_{tot} | $T_C=25\text{ °C}$ | 187 | W |
| Operating and storage temperature | T_j , T_{stg} | - | -55 ... +175 | °C |

| Parameter | Symbol | Conditions | Values | | | Unit |
|------------------------------------------------------|------------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |
| Thermal characteristics⁵⁾ | | | | | | |
| Thermal resistance, junction - case | R_{thJC} | - | - | - | 0.8 | K/W |
| Thermal resistance, junction - ambient ⁴⁾ | R_{thJA} | - | - | 26 | - | |

Electrical characteristics, at $T_j=25^\circ\text{C}$, unless otherwise specified

Static characteristics

| | | | | | | |
|----------------------------------|---------------|-----------------------------------------------------|-----|------|------|---------------|
| Drain-source breakdown voltage | $V_{(BR)DSS}$ | $V_{GS}=0V, I_D=1\text{mA}$ | 40 | - | - | V |
| Gate threshold voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}, I_D=130\mu\text{A}$ | 2.2 | 2.6 | 3.0 | |
| Zero gate voltage drain current | I_{DSS} | $V_{DS}=40V, V_{GS}=0V, T_j=25^\circ\text{C}$ | - | - | 1 | μA |
| | | $V_{DS}=40V, V_{GS}=0V, T_j=125^\circ\text{C}^{2)}$ | - | - | 33 | |
| Gate-source leakage current | I_{GSS} | $V_{GS}=20V, V_{DS}=0V$ | - | - | 100 | nA |
| Drain-source on-state resistance | $R_{DS(on)}$ | $V_{GS}=7V, I_D=60\text{A}$ | - | 0.54 | 0.85 | m Ω |
| | | $V_{GS}=10V, I_D=60\text{A}$ | - | 0.46 | 0.60 | |

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Dynamic characteristics²⁾

| | | | | | | |
|------------------------------|--------------|--------------------------------------------------------|---|------|-------|----|
| Input capacitance | C_{iss} | $V_{GS}=0V, V_{DS}=25V,$ $f=1MHz$ | - | 7607 | 10117 | pF |
| Output capacitance | C_{oss} | | - | 2249 | 2991 | |
| Reverse transfer capacitance | C_{rss} | | - | 100 | 150 | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD}=20V, V_{GS}=10V,$ $I_D=120A, R_G=3.5\Omega$ | - | 13 | - | ns |
| Rise time | t_r | | - | 8 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 33 | - | |
| Fall time | t_f | | - | 16 | - | |

Gate Charge Characteristics²⁾

| | | | | | | |
|-----------------------|---------------|-------------------------------------------------------|---|-----|-----|----|
| Gate to source charge | Q_{gs} | $V_{DD}=32V, I_D=120A,$ $V_{GS}=0 \text{ to } 10V$ | - | 31 | 40 | nC |
| Gate to drain charge | Q_{gd} | | - | 22 | 32 | |
| Gate charge total | Q_g | | - | 116 | 151 | |
| Gate plateau voltage | $V_{plateau}$ | | - | 4.0 | - | V |

Reverse Diode

| | | | | | | |
|------------------------------------------------|---------------|---------------------------------------------|---|-----|------|----|
| Diode continuous forward current ⁵⁾ | I_S | $T_C=25^\circ C$ | - | - | 256 | A |
| Diode pulse current ⁵⁾ | $I_{S,pulse}$ | | - | - | 1780 | |
| Diode forward voltage | V_{SD} | $V_{GS}=0V, I_F=60A,$ $T_j=25^\circ C$ | - | 0.8 | 1.1 | V |
| Reverse recovery time ²⁾ | t_{rr} | $V_R=20V, I_F=50A,$ $di_F/dt=100A/\mu s$ | - | 66 | - | ns |
| Reverse recovery charge ²⁾ | Q_{rr} | | - | 83 | - | nC |

¹⁾ Practically the current is limited by overall system design including customer specific PCB.

²⁾ The parameter is not subject to production test - verified by characterization.

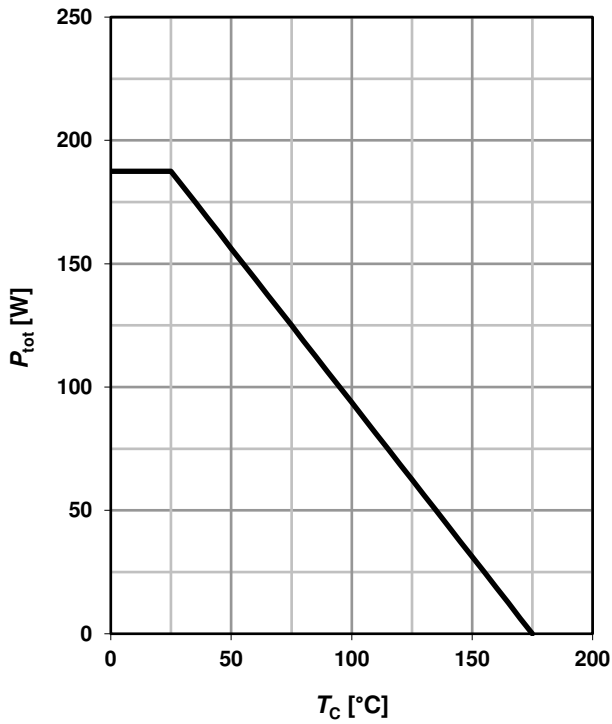
³⁾ The product can operate at specified current based on best practice to minimize electromigration at the solder joint. For rare events and inrush currents the value may be exceeded.

⁴⁾ Device on 2s2p FR4 PCB defined in accordance with JEDEC standards (JESD51-5, -7). PCB is vertical in still air.

⁵⁾ The parameter is not subject to production test - verified by design.

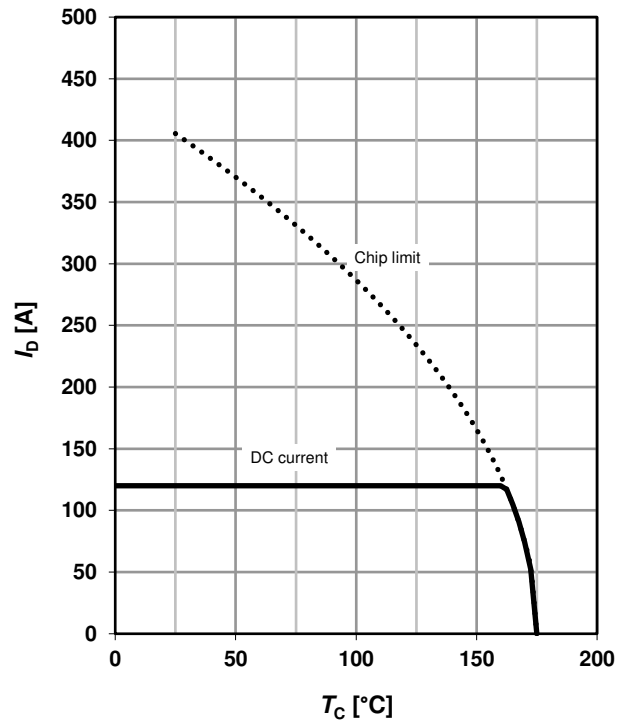
1 Power dissipation

$$P_{\text{tot}} = f(T_C); V_{\text{GS}} = 10 \text{ V}$$



2 Drain current

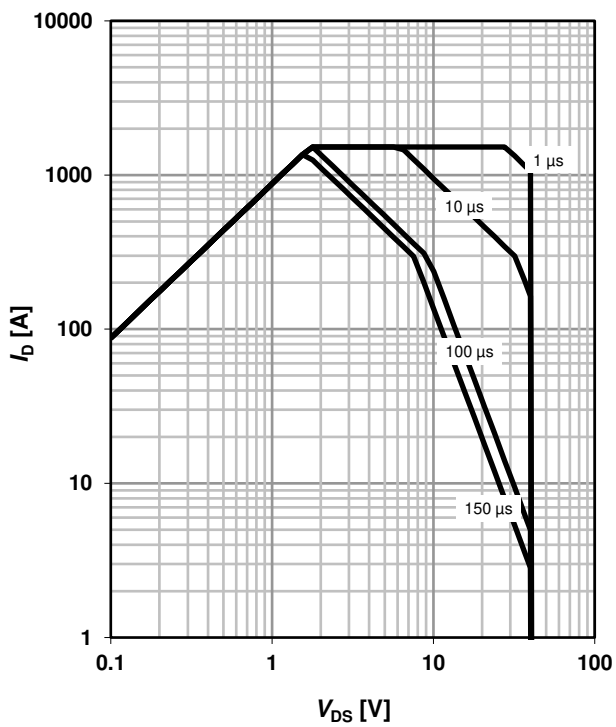
$$I_D = f(T_C); V_{\text{GS}} = 10 \text{ V}$$



3 Safe operating area

$$I_D = f(V_{\text{DS}}); T_C = 25 \text{ °C}; D = 0$$

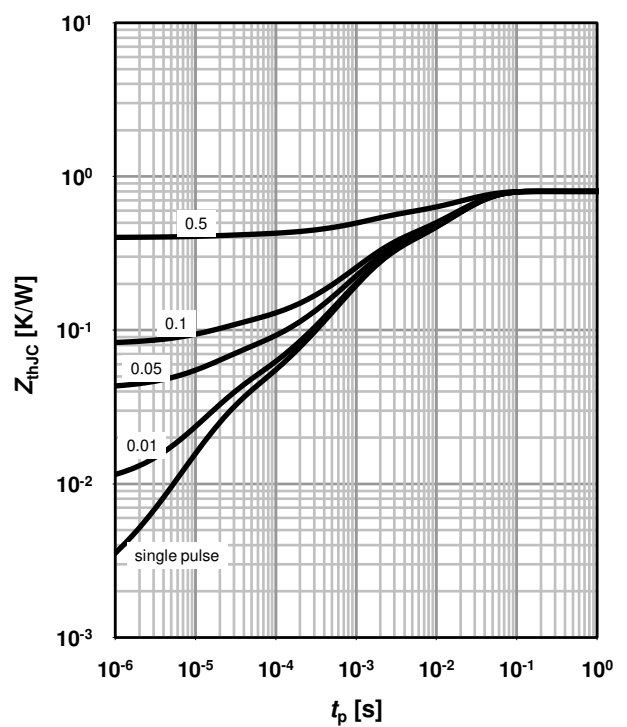
parameter: t_p



4 Max. transient thermal impedance

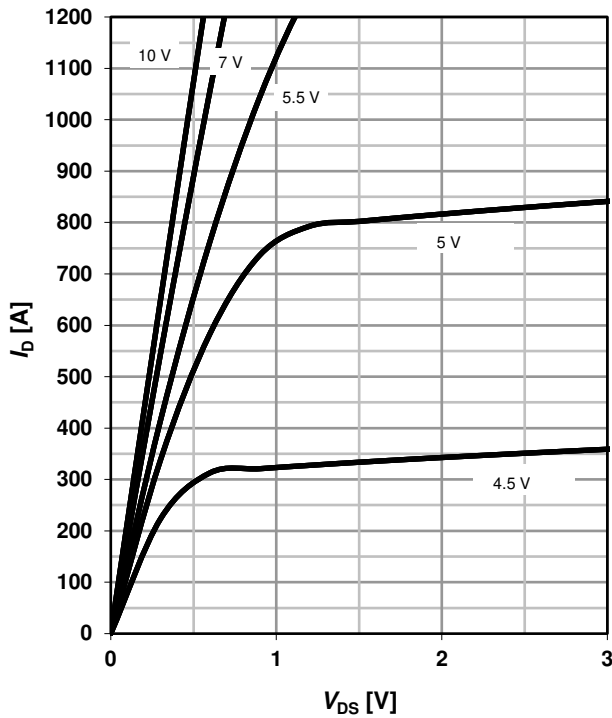
$$Z_{\text{thJC}} = f(t_p)$$

parameter: $D = t_p/T$

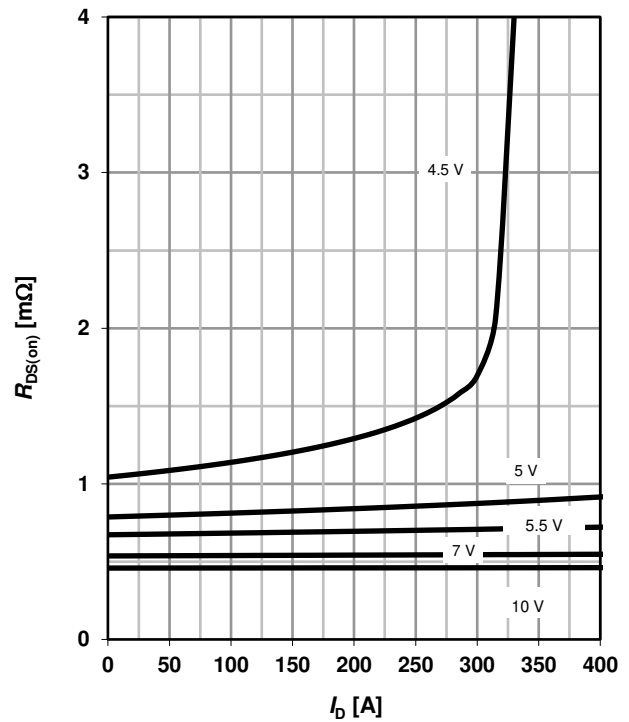


5 Typ. output characteristics

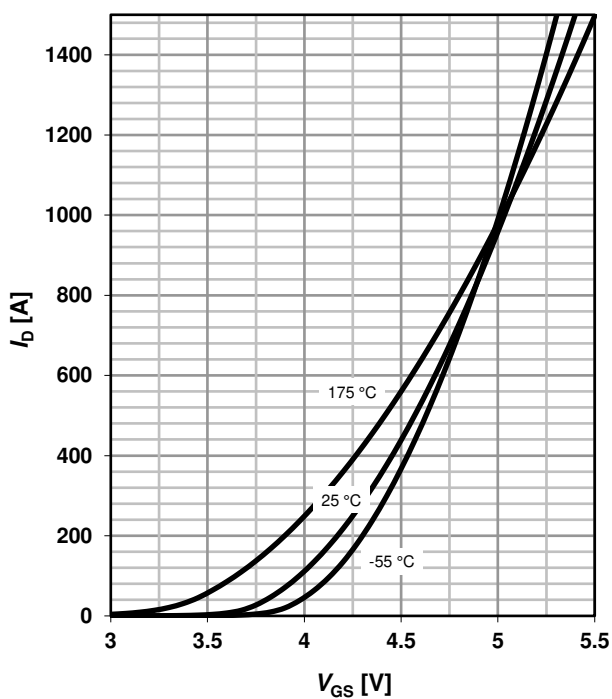
$$I_D = f(V_{DS}); T_j = 25\text{ }^\circ\text{C}$$

 parameter: V_{GS}

6 Typ. drain-source on-state resistance

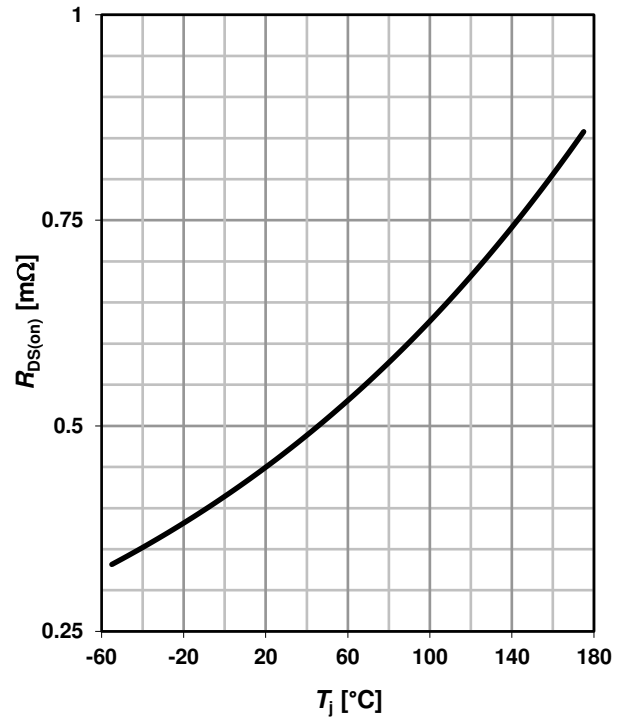
$$R_{DS(on)} = f(I_D); T_j = 25\text{ }^\circ\text{C}$$

 parameter: V_{GS}

7 Typ. transfer characteristics

$$I_D = f(V_{GS}); V_{DS} = 6\text{ V}$$

 parameter: T_j

8 Typ. drain-source on-state resistance

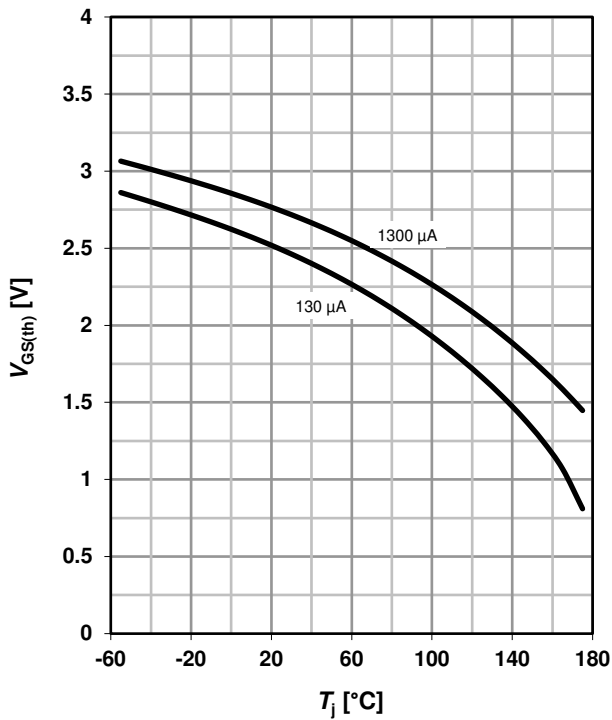
$$R_{DS(on)} = f(T_j); I_D = 60\text{ A}; V_{GS} = 10\text{ V}$$



9 Typ. gate threshold voltage

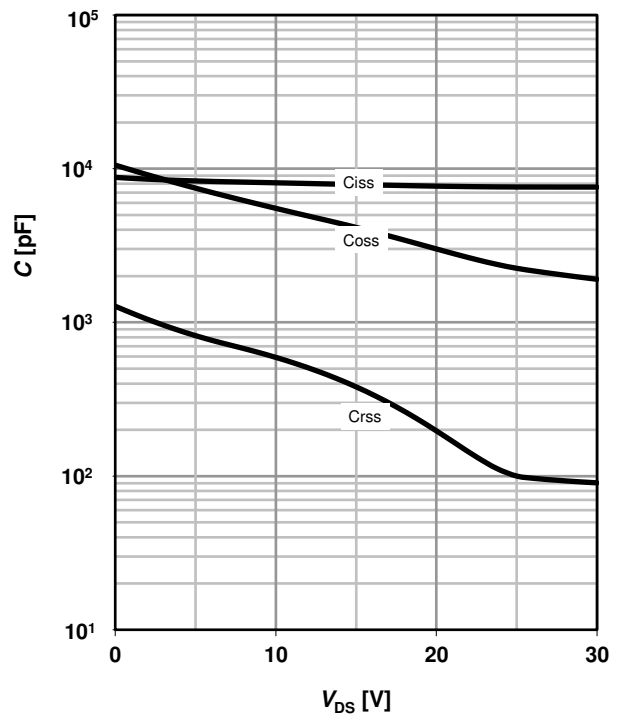
$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D



10 Typ. capacitances

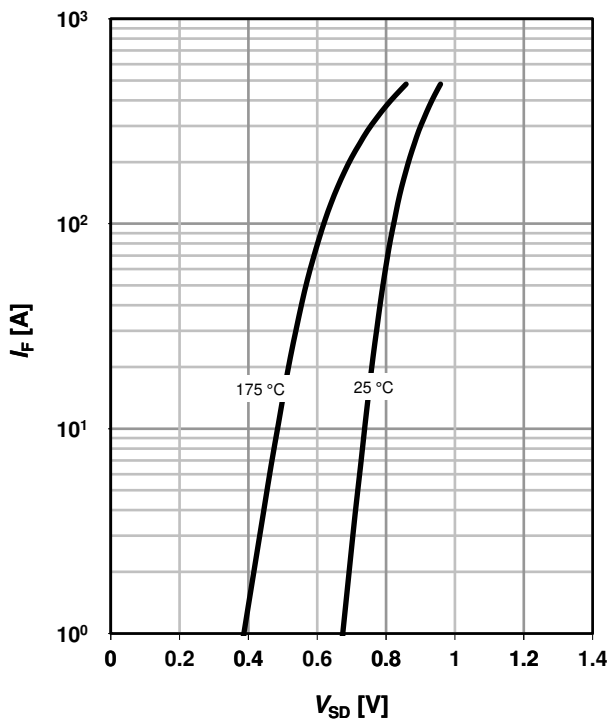
$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$



11 Typical forward diode characteristics

$I_F = f(V_{SD})$

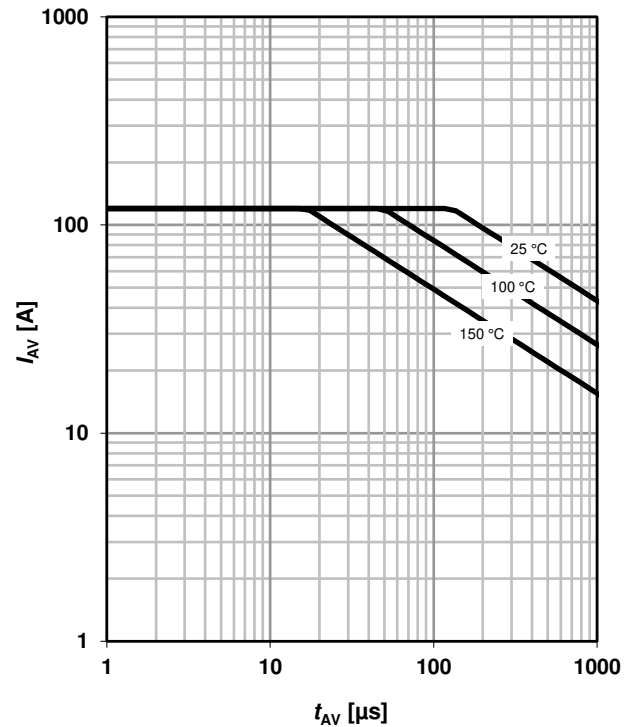
parameter: T_j



12 Avalanche characteristics

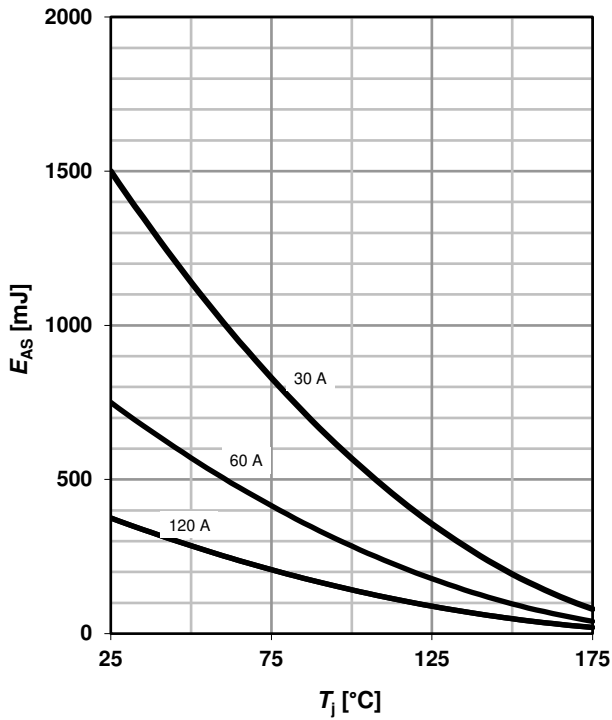
$I_{AS} = f(t_{AV})$

parameter: $T_{j(start)} > 25^\circ\text{C}$

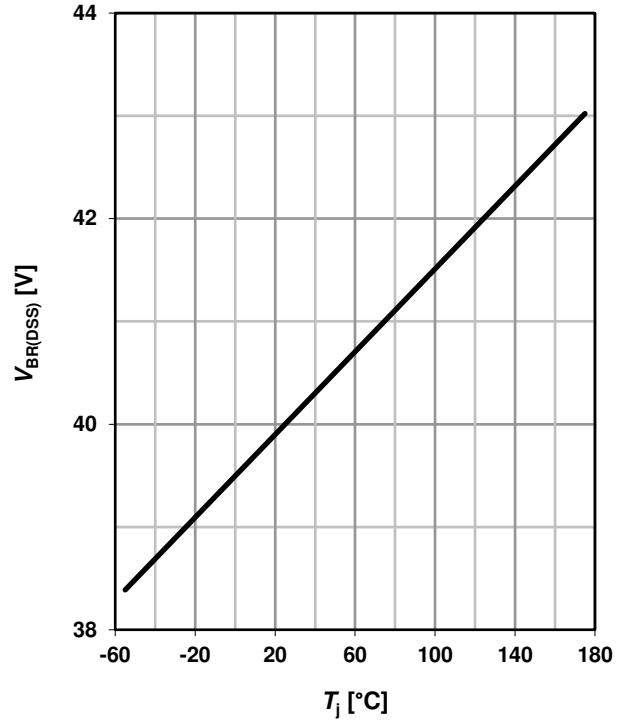


13 Avalanche energy

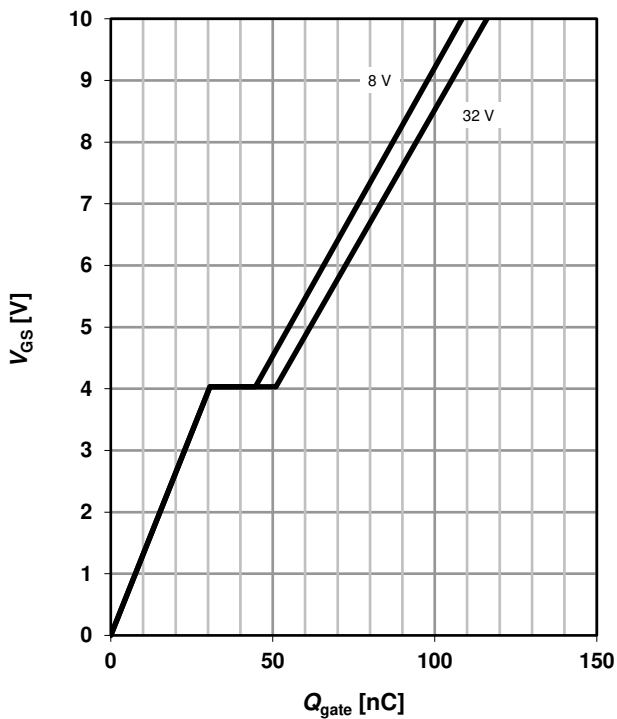
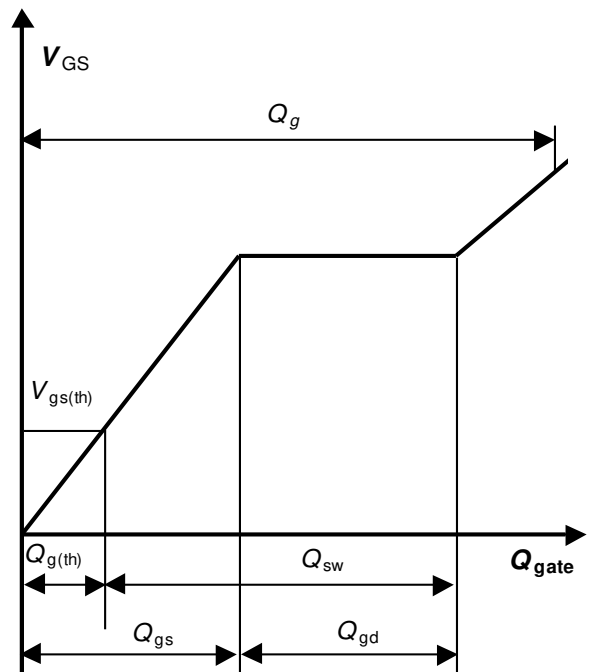
$$E_{AS} = f(T_j)$$


14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$


15 Typ. gate charge

$$V_{GS} = f(Q_{gate}); I_D = 120 \text{ A pulsed}$$

 parameter: V_{DD}

16 Gate charge waveforms


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Revision History

| Version | Date | Changes |
|--------------|------------|------------------|
| Revision 1.0 | 05.06.2020 | Final Data Sheet |
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